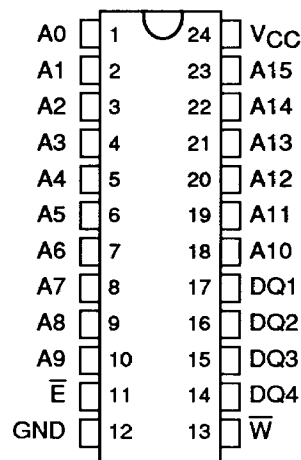


- Organization . . . 65,536 x 4
- Single 5-V Power Supply (10% Tolerance)
- High Density 24-Pin Package
- All Inputs/Outputs Fully TTL Compatible
- Max Access/Min Cycle Time  
TMS6708-20 . . . 20 ns  
TMS6708-25 . . . 25 ns
- Power Saving BiCMOS Technology
- 3-State Output Buffers
- Low Power Dissipation ( $V_{CC} = 5.5\text{ V}$ )  
— Active . . . 550 mW Worst Case  
— Standby . . . 55 mW Worst Case  
(CMOS Input Levels)  
— Standby . . . 165 mW Worst Case  
(TTL Input Levels)

**N AND DJ PACKAGES  
TOP VIEW**



### description

The TMS6708 is a common I/O, 262,144-bit high-speed static random-access memory organized as 65,536 words by 4 bits. The TMS6708 features maximum address access and a minimum cycle times of 20 ns and 25 ns.

The TMS6708 is fabricated using BiCMOS technology. Maximum power dissipation is as low as 550 mW active. This reduces to a maximum of 55 mW (CMOS input levels) and 165 mW (TTL input levels) during standby operation.

All inputs and outputs are compatible with Series 54/74 TTL circuits without the use of external pull-up resistors. Each output can drive one Series 54/74 TTL circuit without external resistors. The data outputs are three-state for connecting multiple devices to a common bus.

The TMS6708 is offered in a 300-mil, 24-pin plastic dual-in-line package (N suffix) and a 24-pin plastic small outline J-lead package (DJ suffix). Both are characterized for operation from 0°C to 70°C.

PIN NOMENCLATURE	
A0-A15	Address Inputs
DQ1-DQ4	Data In/Data Out
$\bar{E}$	Chip Enable
GND	Ground
V <sub>CC</sub>	5-V Power Supply
$\bar{W}$	Write Enable

### operation

#### addresses (A0-A15)

The 16 addresses select one of the 65,536 4-bit words in the RAM. The address inputs must be stable for the duration of a read or write cycle. The address inputs can be driven directly from standard Series 54/74 TTL without external pull-up resistors.

#### chip enable/power down ( $\bar{E}$ )

The chip enable/power down terminal ( $\bar{E}$ ) can be driven directly by standard TTL circuits, and affects the power down/deselect function of a chip. When  $\bar{E}$  is high, the device is put into a reduced power standby mode. Data is retained during the standby mode.

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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# TMS6708

## 262,144-BIT HIGH-SPEED STATIC RANDOM-ACCESS MEMORY

### write enable ( $\overline{W}$ )

The read or write mode is selected through the write enable terminal ( $\overline{W}$ ). A logic high selects the read mode; a logic low selects the write mode.  $\overline{W}$  or  $\overline{E}$  must be high when changing addresses to prevent inadvertently writing data into a memory location. The  $\overline{W}$  input can be driven directly from standard TTL circuits.

### data in /data out (DQ1-DQ4)

Data can be written into a selected device when write enable ( $\overline{W}$ ) is low and chip enable ( $\overline{E}$ ) is low. Data can be read when write enable ( $\overline{W}$ ) is high as chip enable ( $\overline{E}$ ) is low. The DQ terminals can be driven directly from standard TTL circuits. The three-state output buffers provide direct TTL compatibility.

### function table

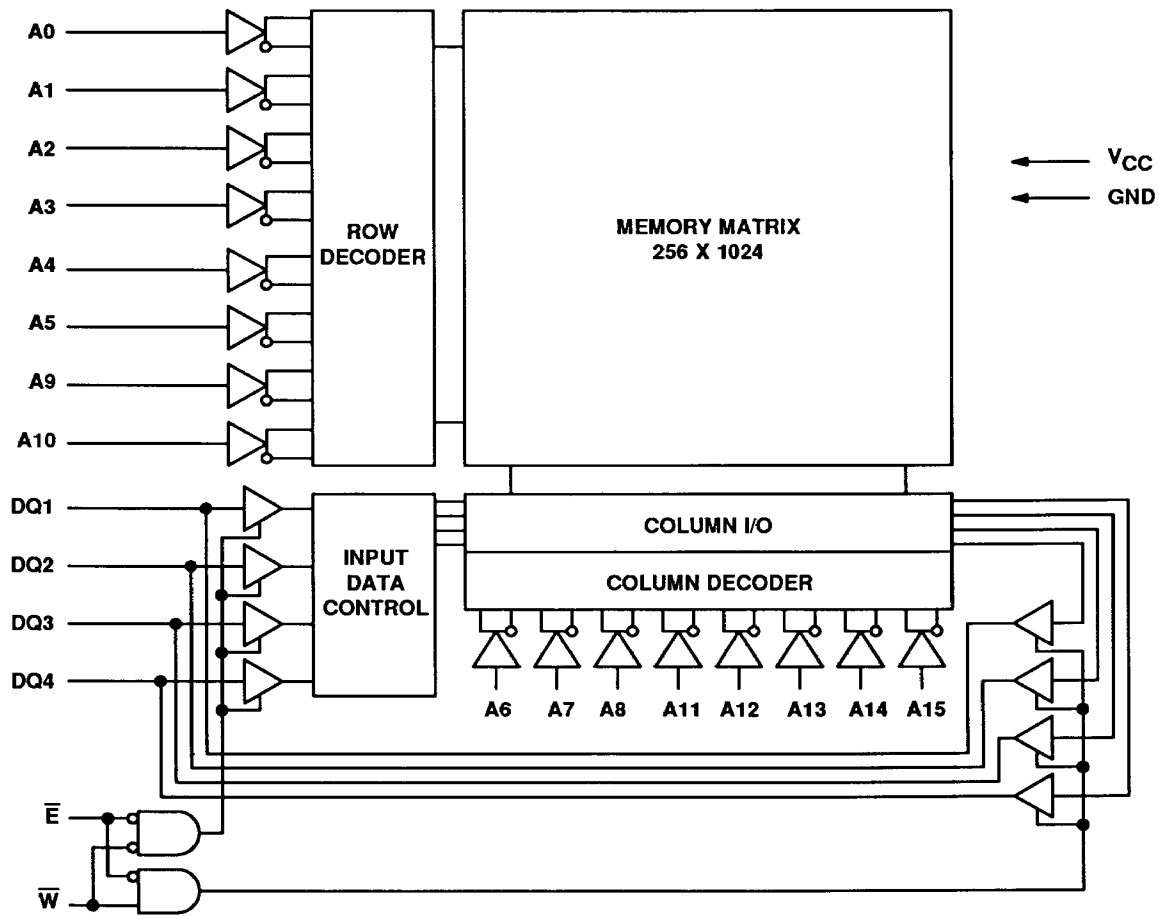
FUNCTION	MODE		
	Deselect	Read	Write
$\overline{W}$	X	H	L
$\overline{E}$	H	L	L
DQ1-DQ4	HI-Z	D <sub>OUT</sub>	D <sub>IN</sub>

X = Don't Care



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functional block diagram

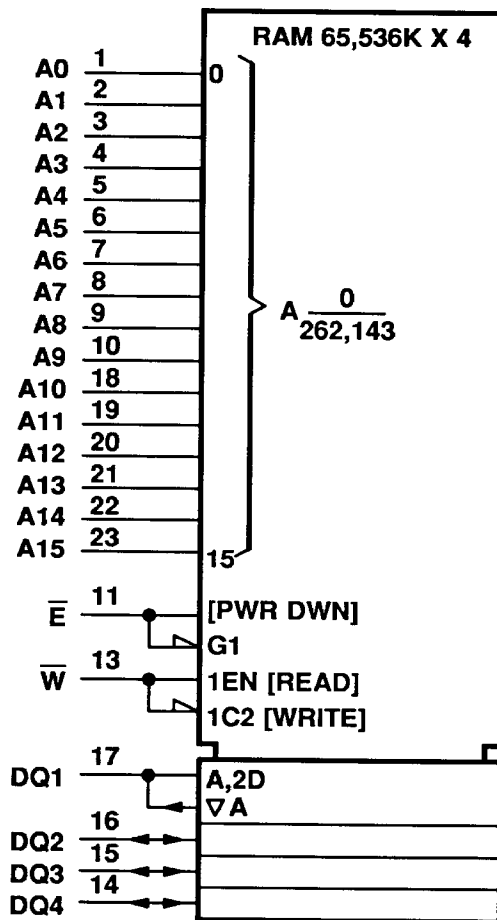


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**TMS6708**  
**262,144-BIT HIGH-SPEED STATIC RANDOM-ACCESS MEMORY**

logic symbol<sup>†</sup>



<sup>†</sup>Symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

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**absolute maximum ratings over operating free-air temperature range (unless other wise noted)<sup>†</sup>**

Supply voltage range (see Note 1)	– 0.5 V to 7 V
Power dissipation	1 W
Operating free-air temperature range	0°C to 70°C
Temperature range powered down	– 10°C to 85°C
Storage temperature range	– 55°C to 125°C

<sup>†</sup>Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions beyond those indicated in the "Recommended Operating Conditions" section of this specification is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to GND terminal.

**recommended operating conditions**

	MIN	NOM	MAX	UNIT
V <sub>CC</sub> Supply voltage	4.5	5.0	5.5	V
V <sub>IH</sub> High-level input voltage	2.2		6	V
V <sub>IL</sub> Low-level input voltage (see Note 2)	– 0.5		0.8	V
T <sub>A</sub> Operating free-air temperature	0		70	°C

NOTE 2: The input voltage may go down to – 3 V for a maximum time interval of 20 ns.

**electrical characteristics over full ranges of recommended operating conditions**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>OH</sub> High level output voltage	I <sub>OH</sub> = – 4 mA	2.4			V
V <sub>OL</sub> Low level output voltage	I <sub>OL</sub> = 8 mA			0.4	V
I <sub>I</sub> Input current (leakage)	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = GND to V <sub>CC</sub>			2	μA
I <sub>O</sub> Output current (leakage)	E = V <sub>IH</sub> , V <sub>I/O</sub> = GND to V <sub>CC</sub>			10	μA
I <sub>CC1</sub> Operating power supply current	E = V <sub>IL</sub> , I <sub>I/O</sub> = 0 mA			100	mA
I <sub>CC2</sub> Average operating current	Minimum cycle, Duty 100%, I <sub>I/O</sub> = 0 mA			120	mA
I <sub>CC(SB1)</sub> Standby supply current (TTL levels)	E = V <sub>IH</sub> , V <sub>in</sub> = V <sub>IH</sub> or V <sub>IL</sub>			30	mA
I <sub>CC(SB2)</sub> Standby supply current (low-power CMOS levels)	E ≥ V <sub>CC</sub> – 0.2 V, V <sub>in</sub> ≤ 0.2 V or V <sub>in</sub> ≥ V <sub>CC</sub> – 0.2 V			10	mA

**capacitance, T<sub>A</sub> = 25°C, f = 1 MHz<sup>‡</sup>**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
C <sub>i</sub> Input capacitance	V <sub>in</sub> = 0 V			6	pF
C <sub>I/O</sub> Output capacitance	V <sub>I/O</sub> = 0 V			10	pF

<sup>‡</sup>Capacitance measurements are made on a sample basis only.

# TMS6708

## 262,144-BIT HIGH-SPEED STATIC RANDOM-ACCESS MEMORY

timing requirements over recommended supply voltage range and operating temperature range (read cycle) (see Note 3)

	ALTERNATE SYMBOL	TMS6708-20		TMS6708-25		UNIT
		MIN	MAX	MIN	MAX	
$t_{c(rd)}$ Read cycle time	$t_{RC}$	20		25		ns

switching characteristics over full ranges of recommended operating conditions (read cycle) (see Note 3)

PARAMETER	ALTERNATE SYMBOL	TMS6708-20		TMS6708-25		UNIT
		MIN	MAX	MIN	MAX	
$t_{a(A)}$ Access time from address	$t_{AA}$		20		25	ns
$t_{a(E)}$ Access time from $\bar{E}$	$t_{ACS}$		20		25	ns
$t_{en(E)}$ Output enable time from $\bar{E}$ (see Note 4)	$t_{LZ}$	0		0		ns
$t_{dis(E)}$ Output disable time from $\bar{E}$ (see Note 4)	$t_{HZ}$	0	8	0	10	ns
$t_{v(A)}$ Output data valid time after address change	$t_{OH}$	5		5		ns

- NOTES: 3. Timing requirements and switching characteristics are defined under the following conditions:
- Input pulse levels ..... GND to 3.0 V
  - Input rise and fall time ..... 4 ns
  - Input timing reference level ..... 1.5 V
  - Output timing reference level ..... 1.5 V
  - Output load (including scope and jig) ..... see Figure 1
4. Transition is measured  $\pm 200$  mV from steady state voltage with specified loading in Figure 1 Load B. This parameter is sampled and not 100% tested.



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timing requirements over recommended supply voltage range and operating temperature range (write cycle) (see Note 3)

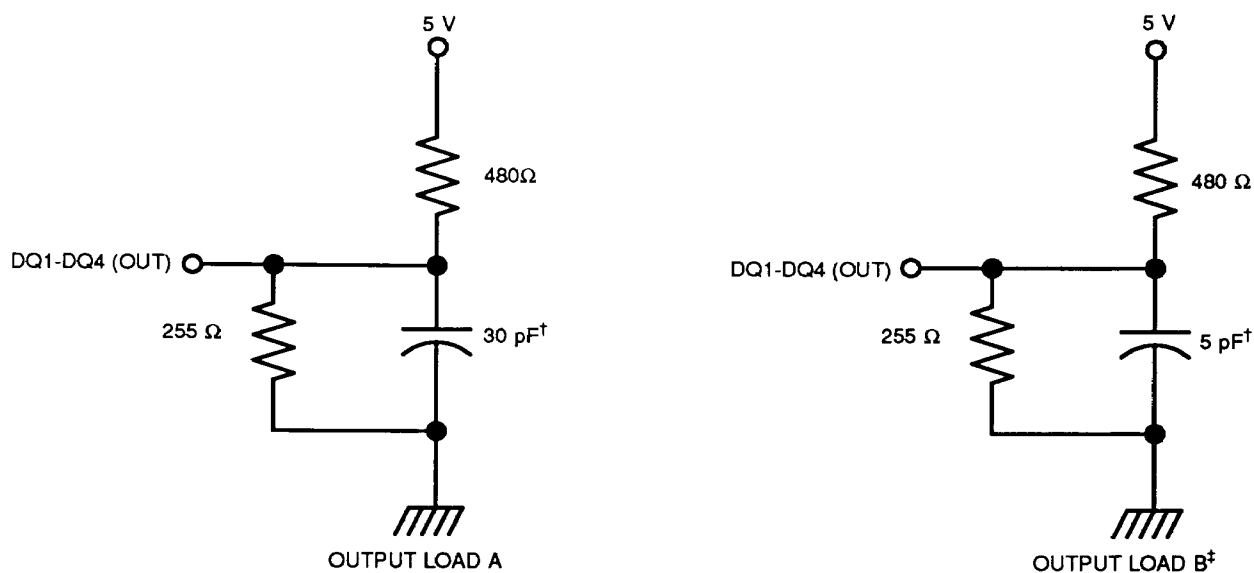
	ALTERNATE SYMBOL	TMS6708-20		TMS6708-25		UNIT
		MIN	MAX	MIN	MAX	
$t_{c(W)}$ Write cycle time (see Note 5)	$t_{WC}$	20		25		ns
$t_{su(E)}$ Chip enable setup time	$t_{CW}$	15		20		ns
$t_{su(A)}$ Address setup time	$t_{AS}$	0		0		ns
$t_{AVWH}$ Address valid time to write high	$t_{AW}$	15		20		ns
$t_{w(W)}$ Write pulse duration	$t_{WP}$	15		20		ns
$t_{rec(W)}$ Write recovery time	$t_{WR}$	3		3		ns
$t_{su(D)}$ Data setup time before write high	$t_{DW}$	12		15		ns
$t_{h(D)}$ Data hold time after write high	$t_{DH}$	0		0		ns
$t_{V(W)}$ Output data valid time after write high (see Note 4)	$t_{OW}$	0		0		ns

switching characteristics over full ranges of recommended operating conditions (write cycle) (see Note 3)

PARAMETER	ALTERNATE SYMBOL	TMS6708-20		TMS6708-25		UNIT
		MIN	MAX	MIN	MAX	
$t_{dis(W)}$ Output disable time from $\overline{W}$ (see Note 4)	$t_{WZ}$	0	8	0	10	ns

- NOTES: 3. Timing requirements and switching characteristics are defined under the following conditions:
- Input pulse levels ..... GND to 3.0 V
  - Input rise and fall time ..... .4 ns
  - Input timing reference level ..... 1.5 V
  - Output timing reference level ..... 1.5 V
  - Output load (including scope and jig) ..... see Figure 1
4. Transition is measured  $\pm 200$  mV from steady state voltage with specified loading in Figure 1 Load B. This parameter is sampled and not 100% tested.
5. All write cycle timings are referenced from the last valid address to the first transitioning address.

PARAMETER MEASUREMENT INFORMATION

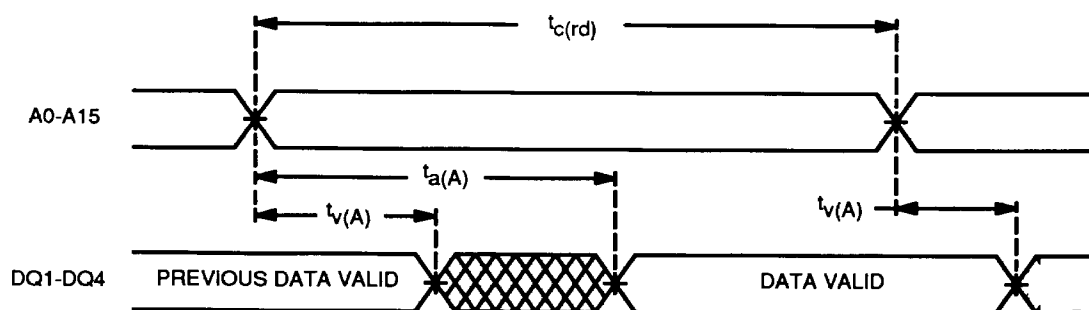


<sup>†</sup>This value includes scope and jig capacitance.

<sup>‡</sup>This output load applies for  $t_{dis}(E)$ ,  $t_{en}(E)$ ,  $t_{dis}(W)$ , and  $t_v(W)$ .

FIGURE 1. OUTPUT LOAD CIRCUIT

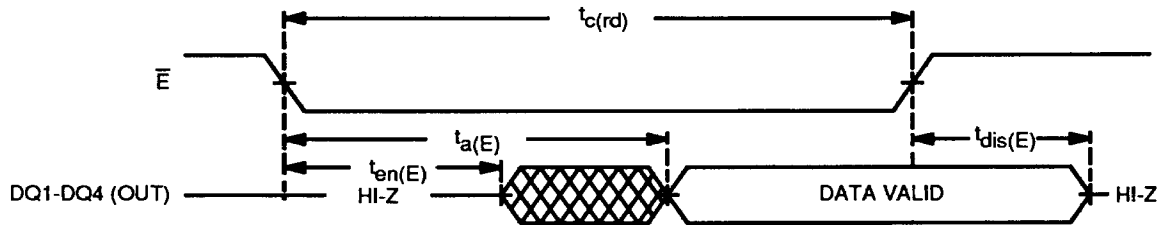
read cycle timing (type A)



NOTES: 6.  $\overline{W}$  is high for the read cycle.

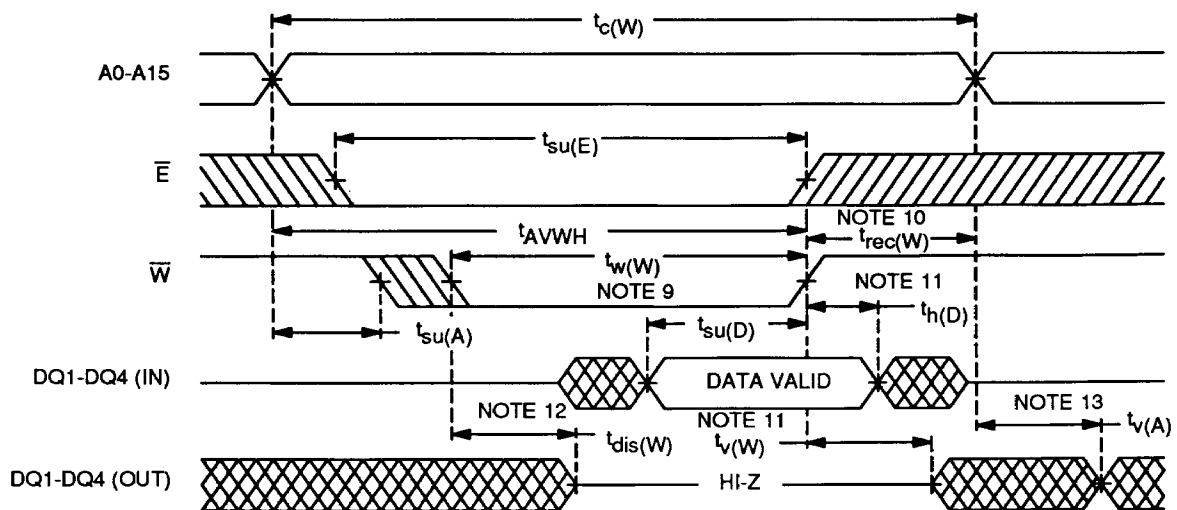
7. Device is continuously selected when  $\overline{E} = V_{IL}$ .

### read cycle timing (type B)



- NOTES: 6.  $\bar{W}$  is high for the read cycle.  
8. Address is valid prior to or at the same time  $\bar{E}$  goes low.

### write cycle timing ( $\bar{W}$ controlled)



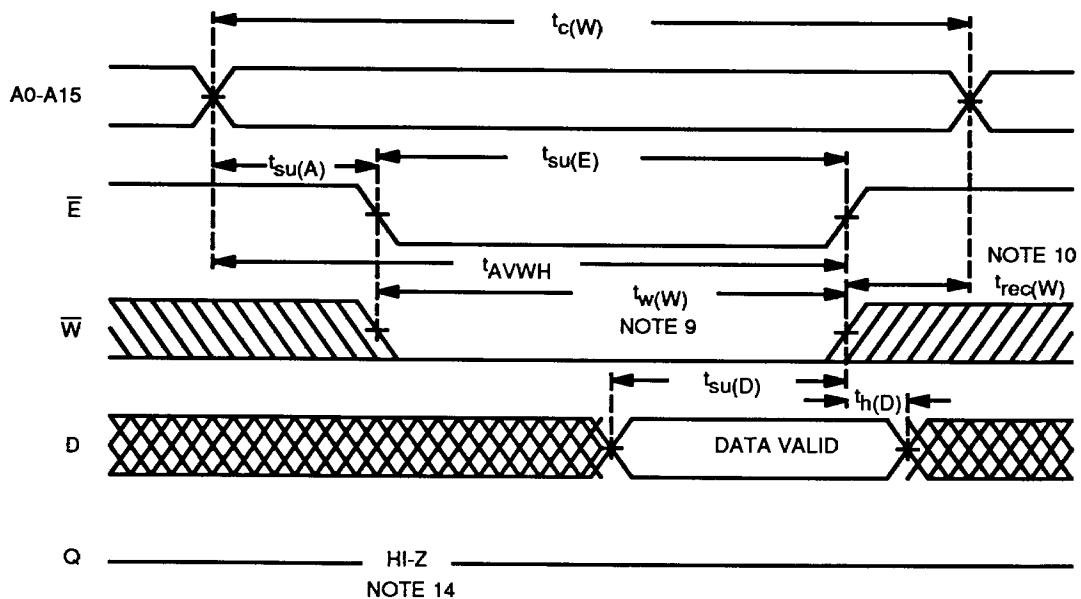
- NOTES: 9. A write occurs during the overlap of a low  $\bar{E}$  and a low  $\bar{W}$  ( $t_w(W)$ ).  
10.  $t_{rec}(W)$  is measured from the earlier of  $\bar{E}$  or  $\bar{W}$  going high to the end of write cycle.  
11. If  $\bar{E}$  is low during this period, I/O pins are in the output state. Then the data input signals of opposite phase to the outputs must not be applied.  
12. During this period, I/O pins are in the output state. The input signals out of phase must not be applied.  
13. DQ1-DQ4 (OUT) is in the same phase as write data in this write cycle.

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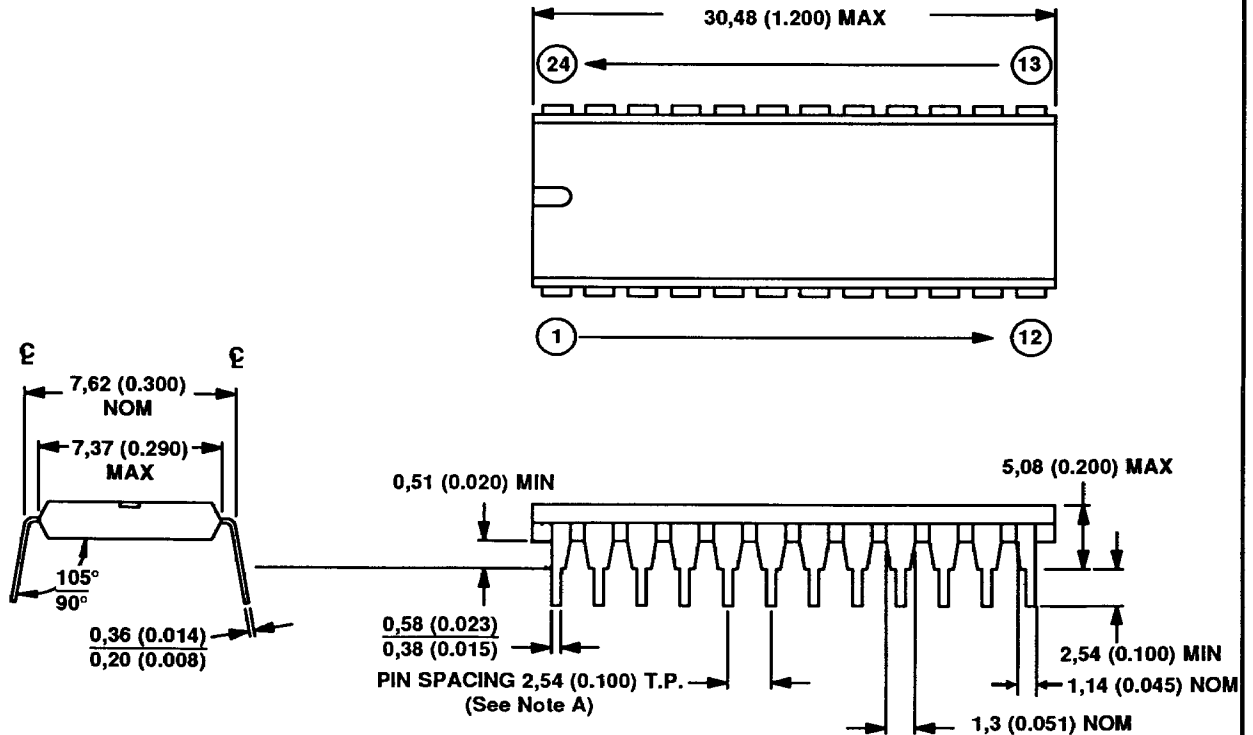
**write cycle timing ( $\overline{E}$  controlled)**



- NOTES: 9. A write occurs during the overlap of a low  $\overline{E}$  and a low  $\overline{W}$  ( $t_w(W)$ ).  
 10.  $t_{rec}(W)$  is measured from the earlier of  $\overline{E}$  or  $\overline{W}$  going high to the end of write cycle.  
 14. If  $\overline{E}$  goes low simultaneously with  $\overline{W}$  going low or after  $\overline{W}$  goes low, the output buffers remain in high-impedance state.

MECHANICAL DATA

24-pin N plastic 300-mil package



ALL LINEAR DIMENSIONS ARE IN MILLIMETERS AND PARENTHETICALLY IN INCHES.

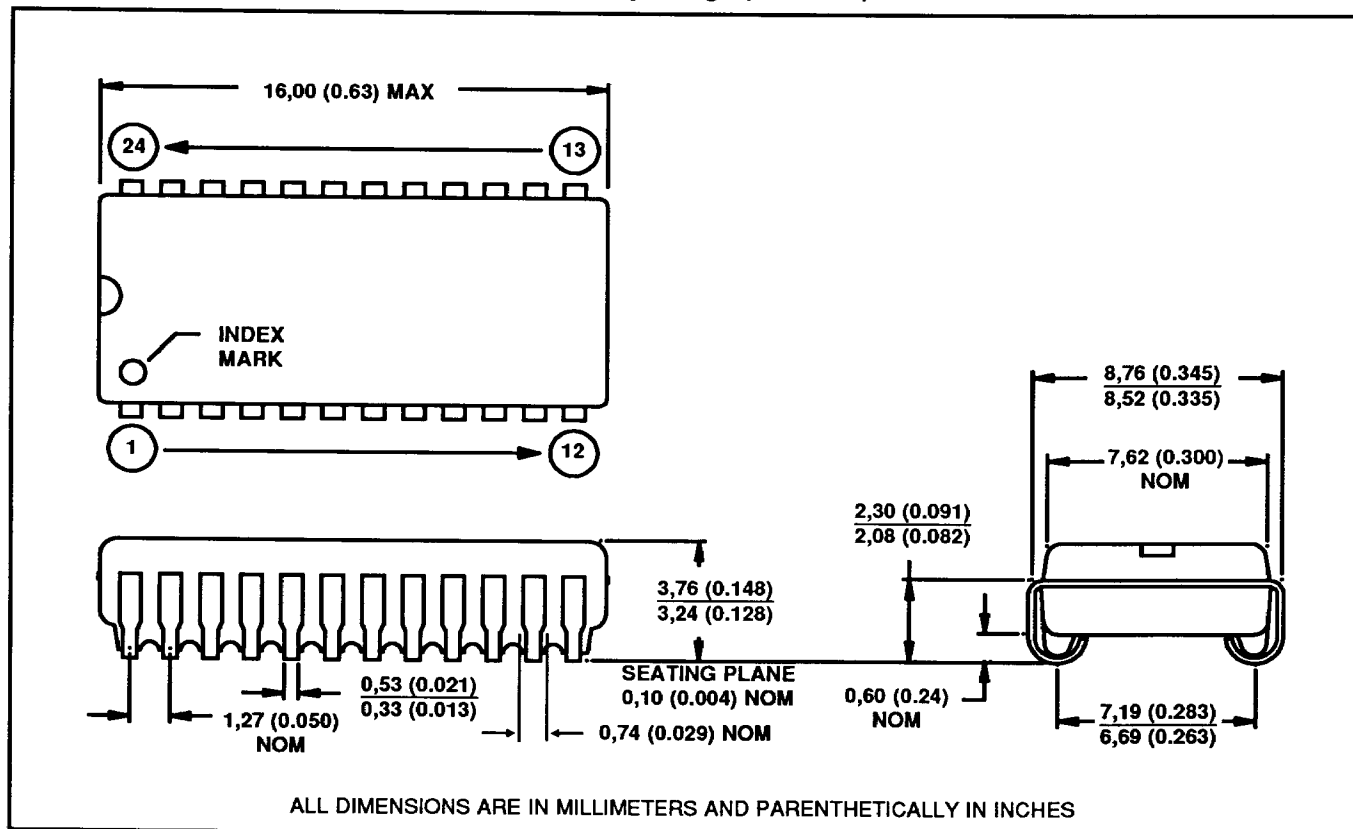
NOTE A: Each pin centerline is located within 0.010 (0.25) of its true longitudinal position.

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MECHANICAL DATA

24-pin plastic small outline J-lead surface mount package (DJ suffix)



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